

Notice of References Cited	Application/Control No. 10/596,543		Applicant(s)/Patent Under Reexamination HEKSTRA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,829,313 B1	12-2004	Xu, Shuzhan J.	714/795
*	B	US-6,901,117 B1	05-2005	Classon et al.	375/341
*	C	US-2001/0044919 A1	11-2001	Edmonston et al.	714/752
*	D	US-2002/0099985 A1	07-2002	Cheng, Jung-Fu	714/704
*	E	US-2004/0148556 A1	07-2004	Hagh et al.	714/755
*	F	US-2004/0223480 A1	11-2004	Nguyen et al.	370/342
*	G	US-6,732,321 B2	05-2004	Classon et al.	714/774
*	H	US-7,092,464 B2	08-2006	Mills, Diane G	375/346
*	I	US-2004/0199848 A1	10-2004	Tamesue et al.	714/758
*	J	US-2004/0234007 A1	11-2004	Mills, Diane G.	375/340
*	K	US-6,871,303 B2	03-2005	Halter, Steven J.	714/702
*	L	US-2005/0111564 A1	05-2005	Kramer et al.	375/265
*	M	US-5,996,104 A	11-1999	Herzberg, Hanan	714/755

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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